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Lucas Laplanche, Alexandre Arnoult, Quentin Gravelier, Stéphane Calvez, Christophe Viallon, et al.. Monolithically integrated 850-nm VCSEL / Electro-Absorption Modulator structures grown by MBE. 22nd International Conference on Molecular Beam Epitaxy (ICMBE 2022), Sep 2022, Sheffield, United Kingdom. 2022. hal-03727282

HAL Id: hal-03727282
<https://laas.hal.science/hal-03727282>

Submitted on 30 Aug 2022

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MONOLITHICALLY INTEGRATED 850-NM VCSEL / ELECTRO-ABSORPTION MODULATOR STRUCTURES GROWN BY MBE

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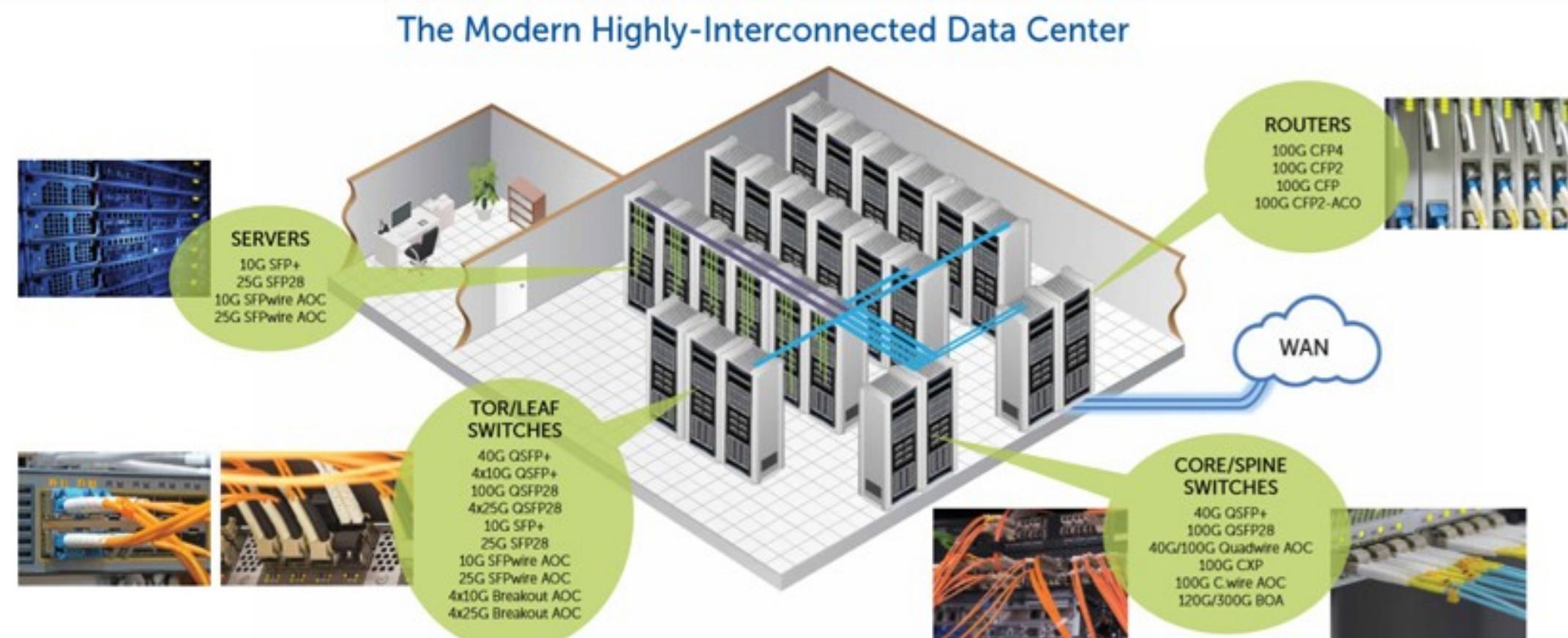


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High-Speed modulation with VCSELs

High speed VCSEL applications:

- Short-reach optical links in Datacenters, supercomputers,..
- LIDAR (3D imaging), mobiles >> 940 nm-arrays
- Optical cables (USB, video)
- Wireless optical links (OWC)
- System on Chip (SoC)
- Quantum computing (Cryogenic readout circuit)



Double microcavity resonant system:

Frequency modulation response, is correlated to the optical coupling between VCSEL and EAM cavities (K. Panajotov et al. doi.org/10.3390/app10176128)

Strong coupling disrupts the VCSEL CW emission

Moderate coupling gives maximized frequency bandwidth

Weak coupling results in small modulation contrast

Growth on
RIBER 412 MBE reactor
on 4" GaAs wafer

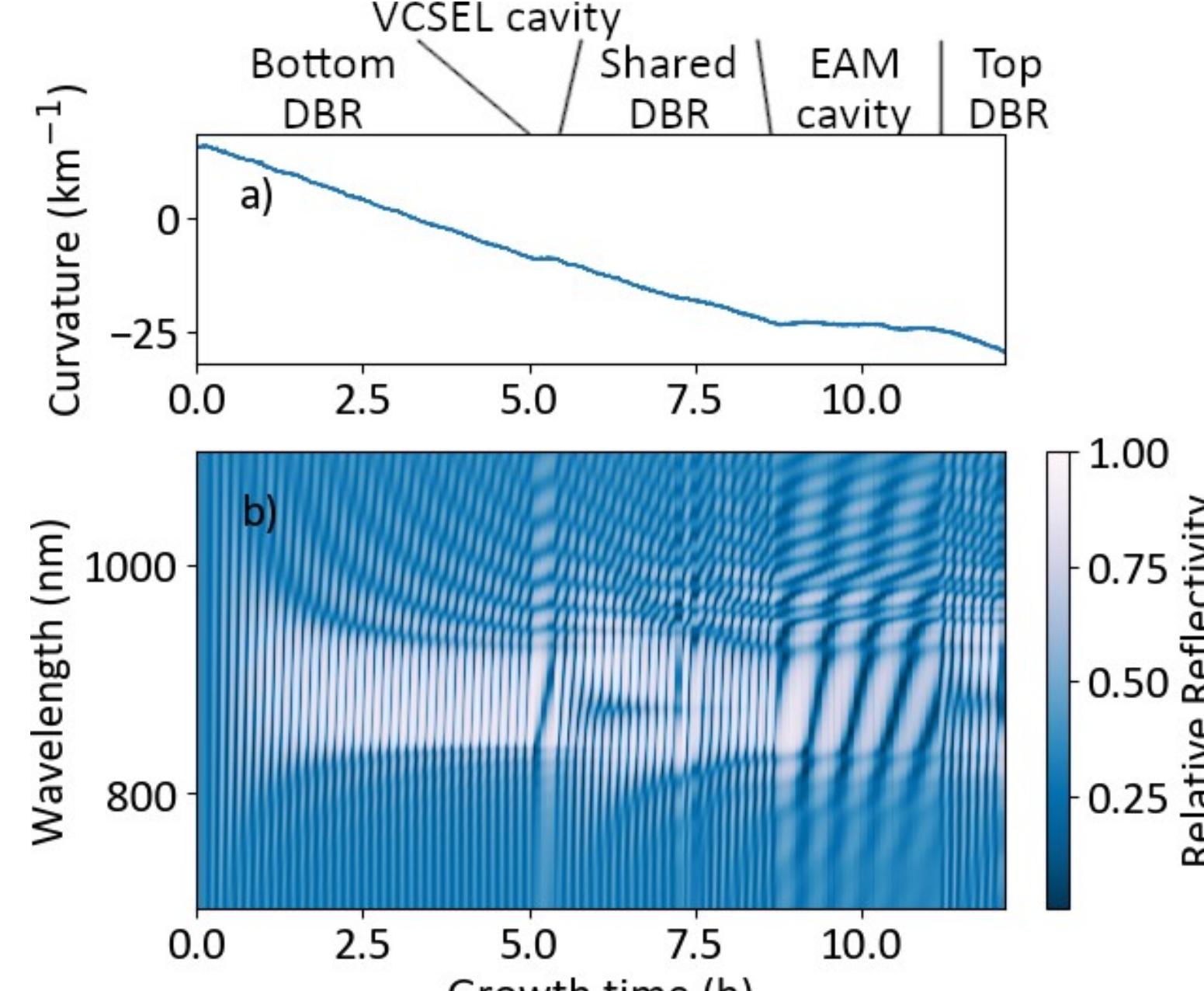
In-situ measurement methods implemented:

Wafer curvature by EZ-CURVE (LAAS patent)

Optical reflectometry 700-1100 nm range

Real-time reflectometry full spectrum allows to:

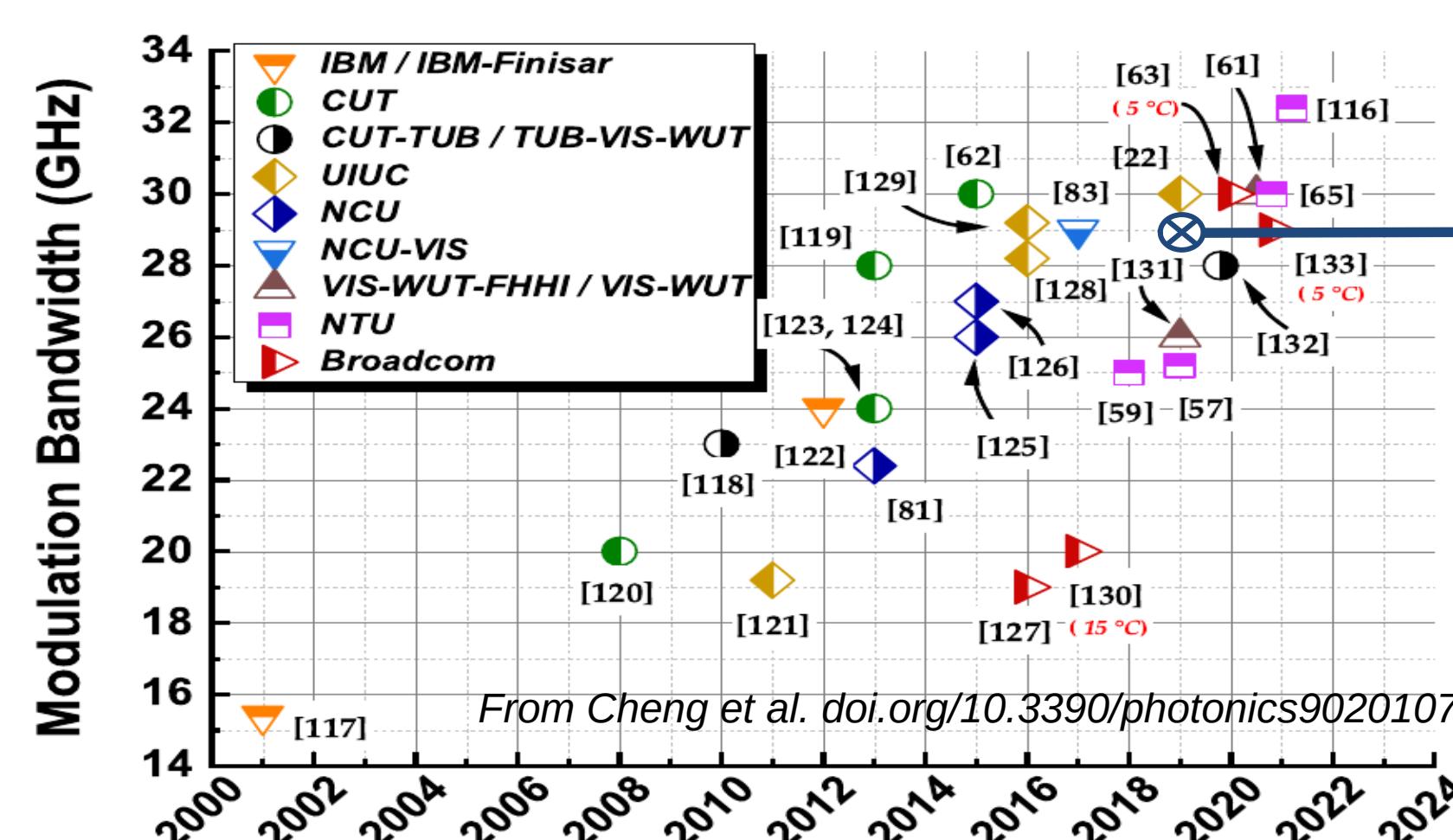
- Check the DBR central wavelength,
- Track the VCSEL FP resonance,
- Track and adjust the middle and top DBR wavelength
- Track and adjust the EAM FP detuning
- **Fab yield increase**



In-situ measurements during the EAM-VCSEL epitaxy:

- a) Wafer curvature
b) Reflectometry

State-of-the-art



Data rate improvement requires:

- Increased intrinsic bandwidth (limited)
- Advanced modulation formats
- Wavelength or Frequency Demultiplexing

Our approach = Vertically Integrated Electro-Absorption Modulator on a VCSEL

First demo: $f_{3dB} = 29\text{GHz}$ in Marigo-Lombart et al. doi.org/10.1088/2515-7647/aaf5af

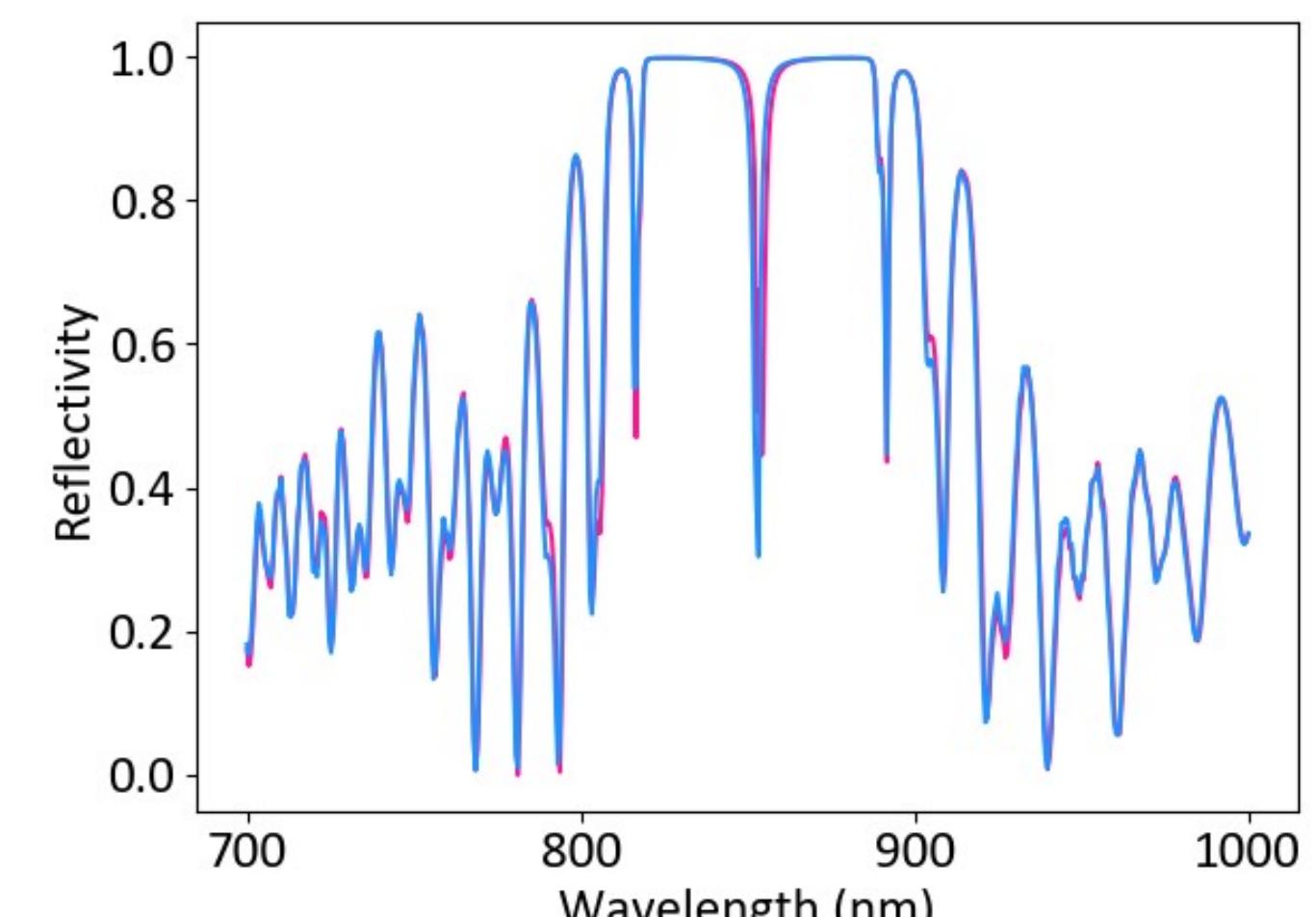
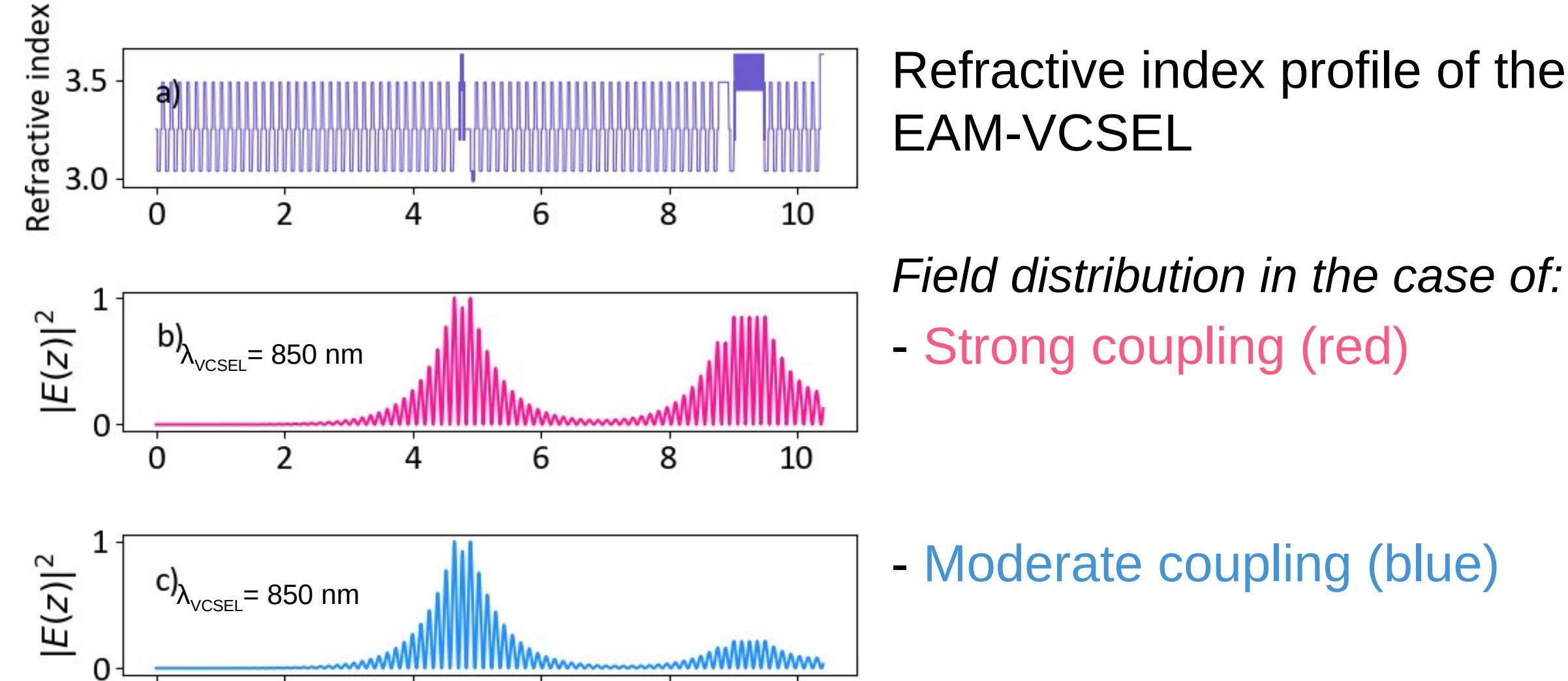
→ Splitting up Emission / Modulation:
CW VCSEL emission + EA Modulation

→ Electro-absorption modulator:
Very high 3dB bandwidth > 65Ghz (Grillanda et al. 2019)

→ High devices density, small footprint

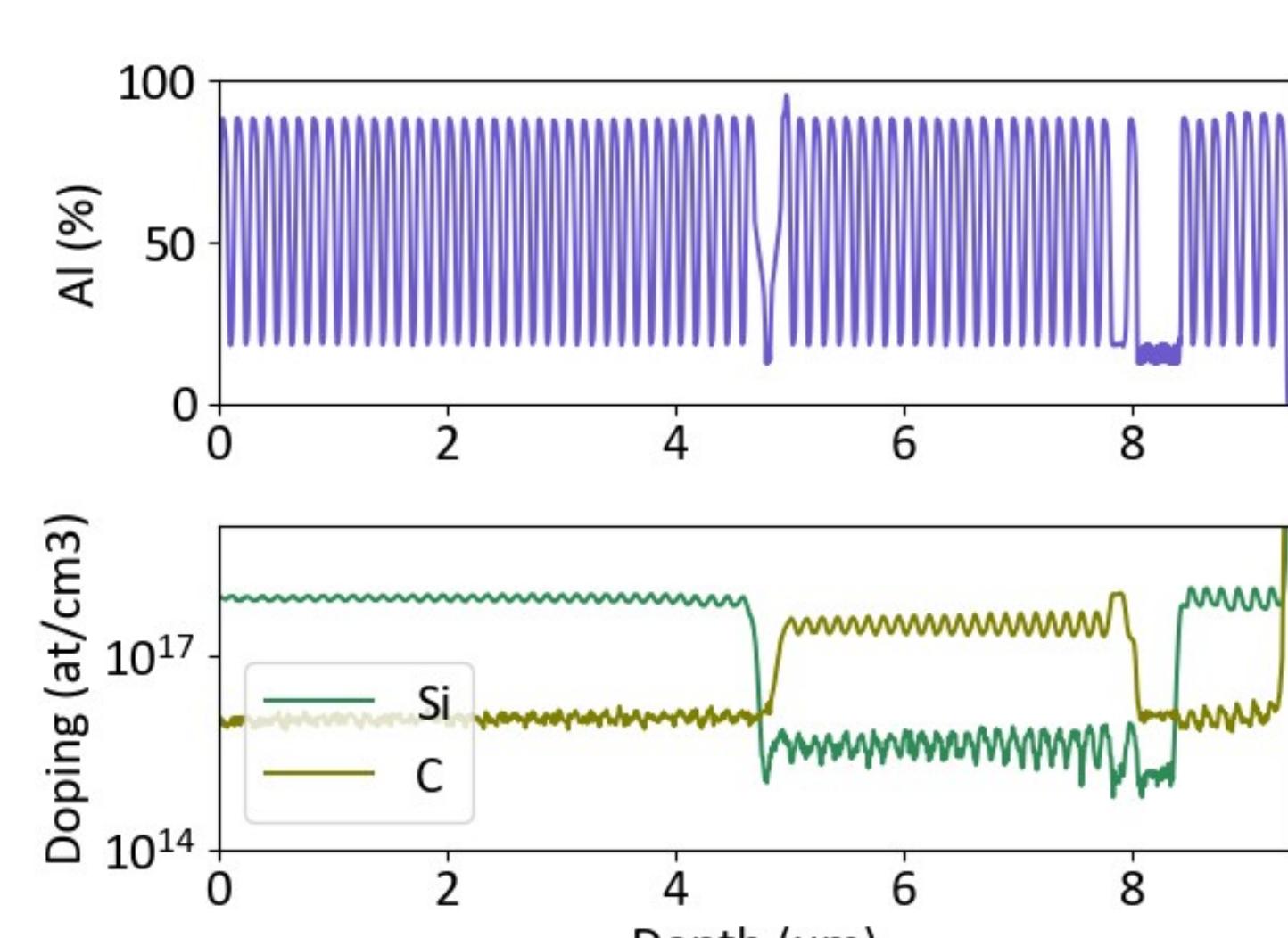
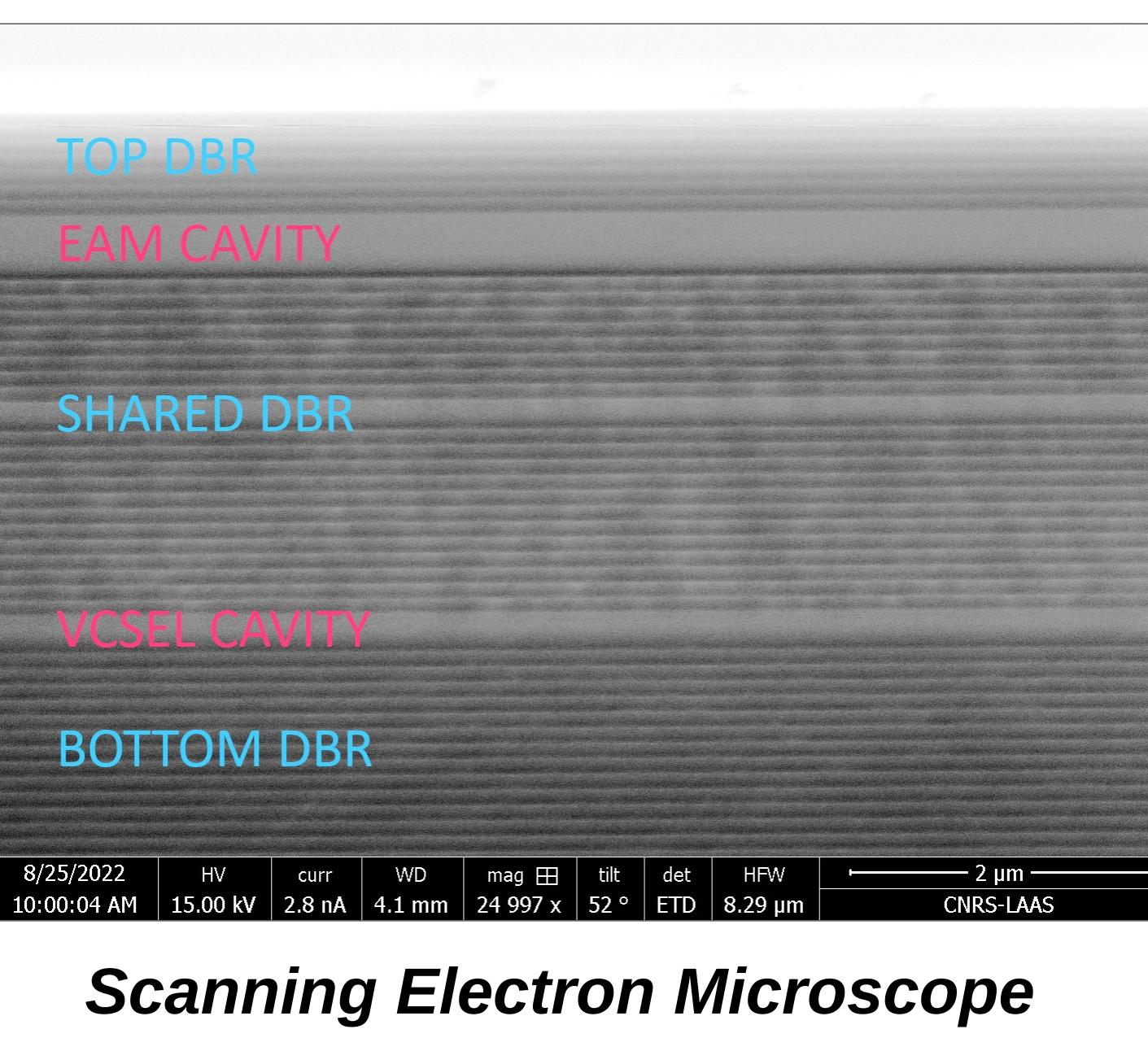
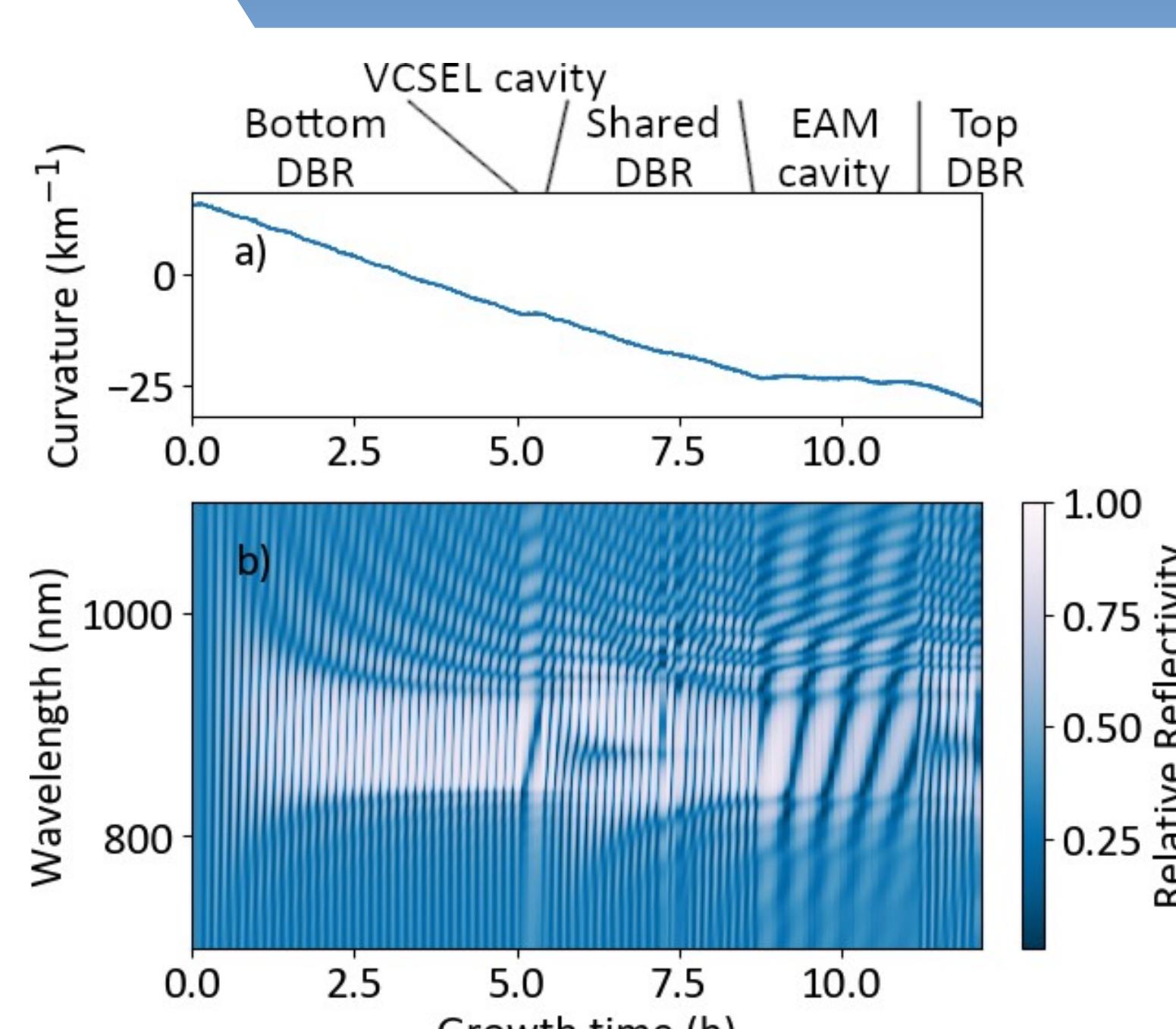
→ Solution not based on direct-current modulation:
Not (intrinsically) limited by carriers/laser dynamics

Modelisation & Design



Calculated reflectivity of the EAM-VCSEL structure

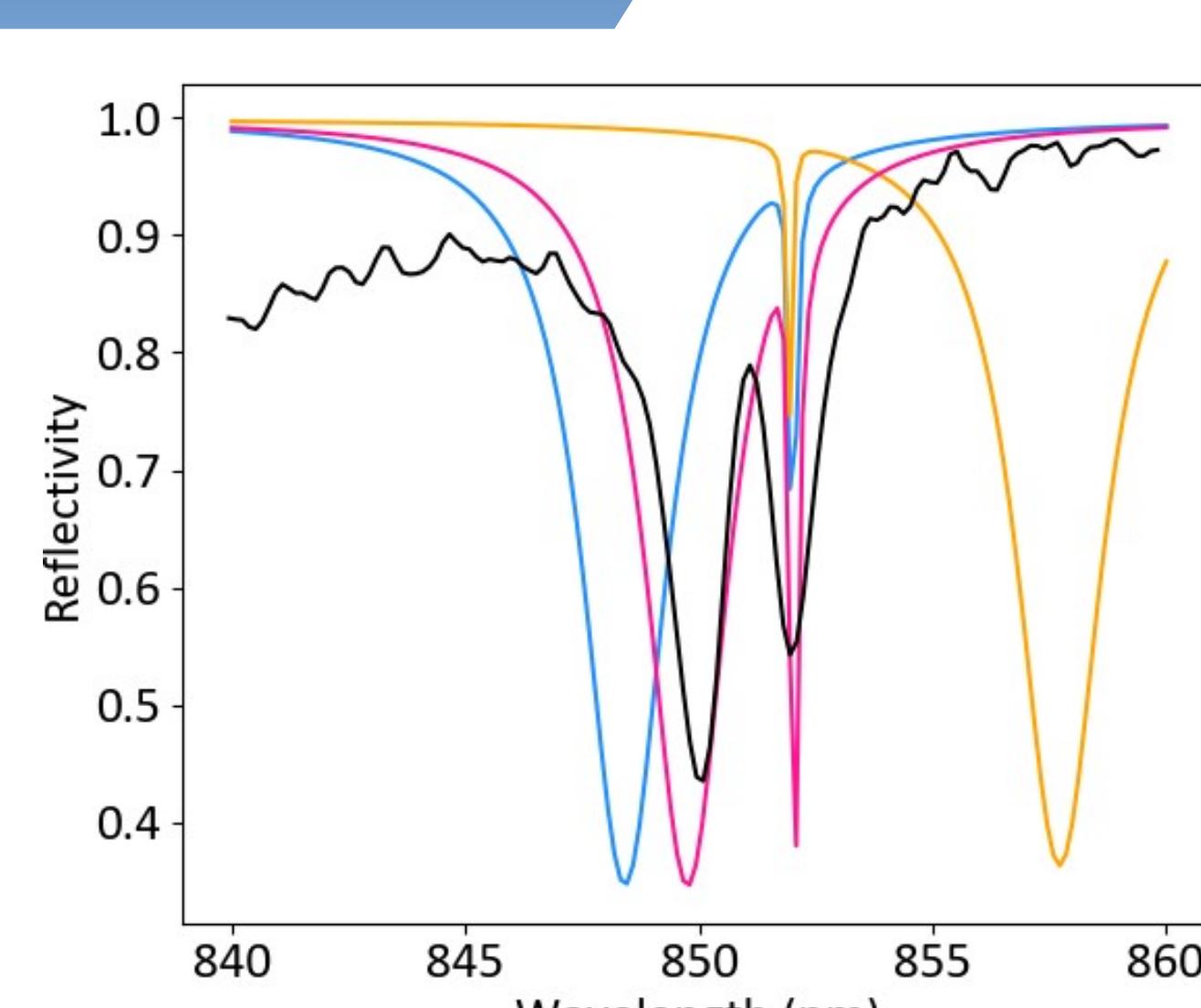
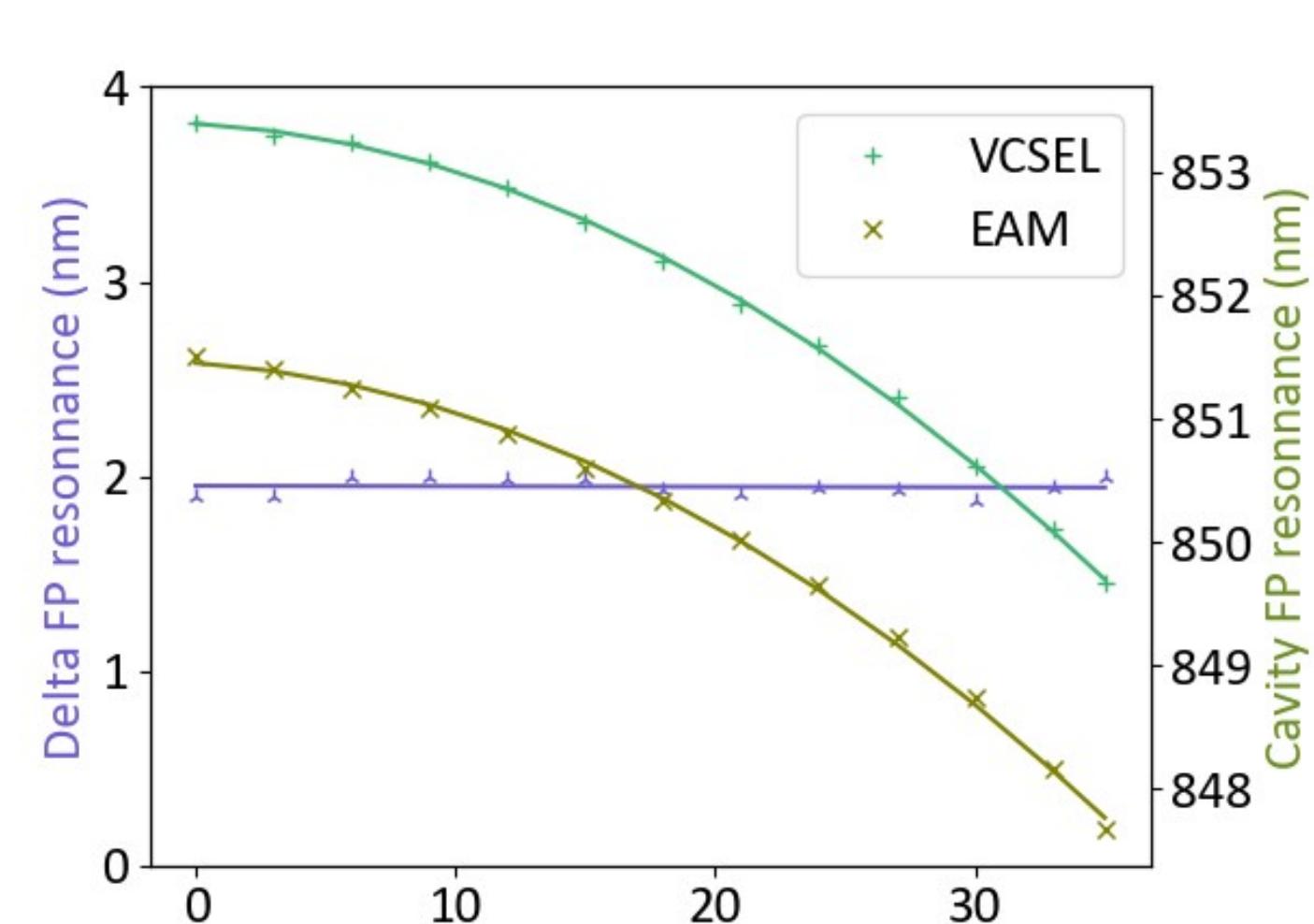
MBE growth



Secondary Ion Mass Spectrometry of the EAM-VCSEL structure

This result highlights that there is no time drift of the AI concentration

Optical results



Room temperature post-growth FTIR reflectivity measurement of the grown EAM-VCSEL structure (black)

Numerical calculation of the reflectivity in the case of:

- Strong coupling (red)
- Moderate coupling (blue, EAM cavity deviation of -3nm)
- Overcoupling (orange, deviation of +7.5nm)

The grown structure exhibits a case of strong coupling

Achievements

- Vertically integrated VCSEL / Electro-absorber modulator (EAM): Original and efficient approach for overpass the limits of directly-modulated VCSELs
- Design/modelling of electro-optical behavior of the EAM-VCSEL
- MBE growth with **in-situ monitoring**: reflectometry + wafer curvature
- EAM-VCSEL growth requires high precision: Best performances (moderate coupling) requires an error of less than +/-0.5% on the EAM cavity thickness

Acknowledgments: RENATECH (French Network of Technology Platforms) at LAAS-CNRS
Project ANR-19-CE24-0018